



HIGH-SPEED 3.3V 256K x 36 SYNCHRONOUS BANK-SWITCHABLE DUAL-PORT STATIC RAM WITH 3.3V OR 2.5V INTERFACE

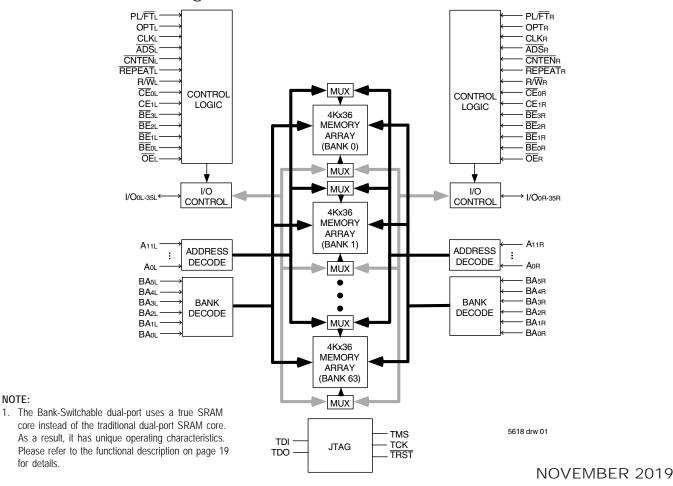
70V7519S

Features:

- 256K x 36 Synchronous Bank-Switchable Dual-ported **SRAM Architecture**
 - 64 independent 4K x 36 banks
 - 9 megabits of memory on chip
- Bank access controlled via bank address pins
- High-speed data access
 - Commercial: 3.4ns(200MHz)/3.6ns (166MHz)/4.2ns (133MHz) (max.)
 - Industrial: 3.6ns (166MHz)/4.2ns (133MHz) (max.)
- Selectable Pipelined or Flow-Through output mode
- Counter enable and repeat features
- Dual chip enables allow for depth expansion without additional logic
- Full synchronous operation on both ports
 - 5ns cycle time, 200MHz operation (14Gbps bandwidth)
 - Fast 3.4ns clock to data out

- 1.5ns setup to clock and 0.5ns hold on all control, data, and address inputs @ 200MHz
- Data input, address, byte enable and control registers
- Self-timed write allows fast cycle time
- Separate byte controls for multiplexed bus and bus matching compatibility
- LVTTL- compatible, 3.3V (±150mV) power supply for core
- LVTTL compatible, selectable 3.3V (±150mV) or 2.5V (±100mV) power supply for I/Os and control signals on each port
- Industrial temperature range (-40°C to +85°C) is available at 166MHz and 133MHz
- Available in a 208-pin fine pitch Ball Grid Array (fpBGA) and 256-pin Ball Grid Array (BGA)
- Supports JTAG features compliant with IEEE 1149.1
- Green parts available, see ordering information

Functional Block Diagram



DSC 5618/11



Description:

The IDT70V7519 is a high-speed 256Kx36 (9Mbit) synchronous Bank-Switchable Dual-Ported SRAM organized into 64 independent 4Kx36 banks. The device has two independent ports with separate control, address, and I/O pins for each port, allowing each port to access any 4Kx36 memory block not already accessed by the other port. Accesses by the ports into specific banks are controlled via the bank address pins under the user's direct control.

Registers on control, data, and address inputs provide minimal setup and hold times. The timing latitude provided by this approach allows systems to be designed with very short cycle times. With an input data

register, the IDT70V7519 has been optimized for applications having unidirectional orbidirectional data flow in bursts. An automatic power down feature, controlled by CEo and CE1, permits the on-chip circuitry of each port to enter a very low standby power mode. The dual chip enables also facilitate depth expansion.

The 70V7519 can support an operating voltage of either 3.3V or 2.5V on one or both ports, controllable by the OPT pins. The power supply for the core of the device(VDD) remains at 3.3V. Please refer also to the functional description on page 19.

Pin Configuration (1,2,3,4)

A1 IO19L	A2 IO18L	A3 Vss	A4 TDO	A5 NC	A6 BA4L	A7 BA0L	A8 A8L	A9 BE1L	A10 VDD	A11 CLKL	A12 CNTENL	A13 A 4L	A14 A0L	A15 OPTL	A16 I/O17L	A17 Vss
B1 I/O20R	B2 Vss	B3 I/O18R	B4 TDI	B5 BA5L	B6 BA1L	B7 A 9L	B8 BE2L	B9 CE0L	B10 Vss	B11 ADSL	B12 A 5L	B13 A 1L	B14 Vss	B15 VDDQR	B16 I/O16L	B17 I/O15R
C1 VDDQL	C2 I/O19R	C3 Vddqr	C4 PL/FTL	C5 NC	C6 BA2L	C7 A 10L	C8 BE3L	C9 CE1L	C10 Vss	C11 R/WL	C12 A 6L	C13 A 2L	C14 VDD	C15 I/O16R	C16 I/O15L	C17 Vss
D1 I/O22L	D2 Vss	D3 I/O21L	D4 I/O20L	D5 BA3L	D6 A11L	D7 A 7L	D8 BE0L	D9 VDD	D10 OEL	D 11 REPEATL	D12 A 3L	D13 VDD	D14 I/O17R	D15 VDDQL	D16 I/O14L	D17 I/O14R
E1 I/O23L	E2 I/O22R	E3 Vddqr	E4 I/O21R								-		E14 I/O12L	E15 I/O13R	E16 Vss	E17 I/O13L
F1 VDDQL	F2 I/O23R	F3 I/O24L	F4 Vss										F14 Vss	F15 I/O12R	F16 I/O11L	F17 VDDQR
G1 I/O26L	G2 Vss	G3 I/O25L	G4 I/O24R										G14 I/O9L	G15 VDDQL	G16 I/O10L	G17 I/O11R
H1 VDD	H2 I/O26R	H3 Vddqr	H4 I/O25R				_)V75 ⁻ F208	-				H14 VDD	H15 IO9R	H16 Vss	H17 I/O10R
J1 VDDQL	J2 Vdd	^{J3} Vss	J4 Vss			,							J14 Vss	J15 Vdd	J16 Vss	J17 Vddqr
K1 I/O28R	K2 Vss	K3 I/O27R	K4 Vss			4		Pin fp		1			K14 I/O7R	K15 VddQl	K16 I/O8R	K17 V SS
L1 I/O29R	L2 I/O28L	l3 Vddqr	L4 I/O27L										L14 I/O6R	L15 I/O7L	L16 Vss	L17 I/O8L
M1 VDDQL	M2 I/O29L	M3 I/O30R	M4 Vss										M14 Vss	M15 I/O6L	M16 I/O5R	M17 VDDQR
N1 I/O31L	N2 Vss	N3 I/O31R	N4 I/O30L										N14 I/O3R	N15 VDDQL	N16 I/O4R	N17 I/O5L
P1 I/O32R	P2 I/O32L	p3 Vddqr	P4 I/O35R	P5 TRST	P6 BA4R	P7 BAor	P8 A 8R	P9 BE1R	P10 VDD	P11 CLKR	P12 CNTENR	P13 A 4R	P14 I/O2L	P15 I/O3L	P16 Vss	P17 I/O4L
R1 Vss	R2 I/O33L	R3 I/O34R	R4 TCK	R5 BA5R	R6 BA1R	R7 A 9R	R8 BE2R	R9 CE0R	R10 Vss	R11 ADSR	R12 A 5R	R13 A1R	R14 Vss	R15 Vddql	R16 I/O1R	R17 VDDQR
T1 I/O33R	T2 I/O34L	T3 Vddql	T4 TMS	T5 NC	T6 BA2R	T7 A 10R	T8 BE3R	T9 CE1R	T10 Vss	T11 R/WR	T12 A 6R	T13 A 2R	T14 Vss	T15 I/O0R	T16 Vss	T17 I/O2R
U1 Vss	U2 I/O35L	uз PL/FTR	U4 NC	U5 B A 3R	U6 A 11R	U7 A 7R	U8 BEor	U9 Vdd	U10 OEr	U11 REPEATR	U12 A 3R	U13 A 0R	U14 VDD	U15 OPTR	U16 I/O0L	U17 I/O1L

5618 drw 02c

- 1. All VDD pins must be connected to 3.3V power supply.
- 2. All VDDQ pins must be connected to appropriate power supply: 3.3V if OPT pin for that port is set to VIH (3.3V), and 2.5V if OPT pin for that port is set to VIL (0V).
- 3. All Vss pins must be connected to ground supply.
- 4. Package body is approximately 15mm x 15mm x 1.4mm with 0.8mm ball pitch.
- 5. This package code is used to reference the package diagram.
- 6. This text does not indicate orientation of the actual part-marking.

Pin Configuration^(1,2,3,4) (con't.)

70V7519 BC256⁽⁵⁾

256-Pin BGA Top View⁽⁶⁾

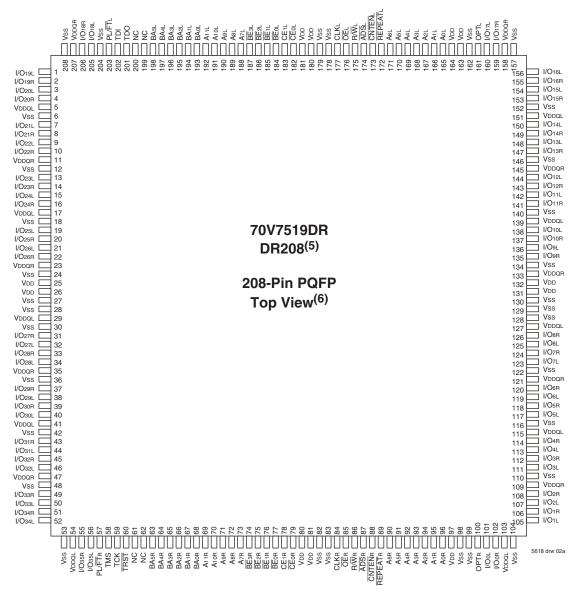
A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16
NC	TDI	NC	BA5L	BA2L	A 11L	A 8L	BE ₂ L	CE1L	OEL	CNTENL	A 5L	A 2L	A 0L	NC	NC
B1 I/O18L	NC	B3 TDO	NC	B5 BA3L	B6 BA0L	B7 A 9L	B8 BE3L	B9 CE ₀ L	B10 R/WL	B11 REPEATL	B12 A 4L	B13 A 1L	B14 VDD	B15 I/O17L	B16 NC
C1	C2	C3	C4	C5	C6	C7	C8	C9	C10	C11	C12	C13	C14	C15	C16
I/O18R	I/O19L	Vss	B A 4L	BA1L	A 10L	A 7L	BE ₁ L	BE ₀ L	CLKL	ADSL	A 6L	A 3L	OPTL	I/O17R	I/O16L
D1	D2	D3	D4	D5	D6	d7	d8	D9	d10	D11	D12	D13	D14	D15	D16
I/O20R	I/O19R	I/ O 20L	PL/FTL	Vddql	Vddql	Vddqr	Vddqr	VDDQL	Vddql	VDDQR	VDDQR	VDD	I/O15R	I/O15L	I/O16R
E1	E2	E3	E4	E5	E6	E7	E8	E9	E10	E11	E12	E13	E14	E15	E16
I/O21R	I/O21L	I/O22L	VDDQL	Vdd	VDD	V SS	Vss	Vss	Vss	VDD	VDD	Vddqr	I/O13L	I/O14L	I/O14R
F1	F2	F3	F4	F5	F6	F7	F8	F9	F10	F11	F12	F13	F14	F15	F16
I/O23L	I/O22R	I/ O 23R	V DDQL	Vdd	Vss	Vss	Vss	Vss	Vss	Vss	VDD	Vddqr	I/O12R	I/O13R	I/O12L
G1	G2	G3	G4	G5	G6	G7	G8	G9	G10	G11	G12	G13	G14	G15	G16
I/ O 24R	I/O24L	I/ O 25L	Vddqr	Vss	Vss	V SS	Vss	Vss	Vss	Vss	Vss	VDDQL	I/O10L	I/O11L	I/O11R
H1	H2	H3	h4	H5	H6	H7	нв	H9	H10	H11	H12	H13	H14	H15	H16
I/O26L	I/O25R	I/ O 26R	Vddqr	Vss	Vss	V SS	Vss	Vss	Vss	Vss	Vss	VDDQL	I/O9R	IO 9L	I/O10R
J1	J2	J3	J4	J5	J6	J7	J8	J9	J10	J11	J12	J13	J14	J15	J16
I/ O 27L	I/ O 28R	I/ O 27R	V DDQL	Vss	Vss	V SS	V SS	Vss	V ss	Vss	Vss	Vddqr	I/O8R	I/ O 7R	I/O8L
K1	K2	K3	K4	K5	K6	K7	K8	K9	K10	K11	K12	K13	K14	K15	K16
I/O29R	I/ O 29L	I/O28L	Vddql	Vss	Vss	Vss	Vss	Vss	Vss	Vss	Vss	VDDQR	I/O6R	I/O6L	I/O7L
L1	L2	L3	L4	L5	L6	L7	L8	L9	L10	L11	L12	L13	L14	L15	L16
I/O30L	I/O31R	I/ O 30R	Vddqr	VDD	Vss	Vss	Vss	Vss	Vss	Vss	Vdd	VDDQL	I/O5L	I/O4R	I/ O 5R
M1	M2		m4	M5	M6	M7	M8	м9	M10	M11	M12	M13	M14	M15	M16
I/O32R	I/O32L		Vddqr	VDD	VDD	Vss	Vss	Vss	V SS	VDD	VDD	VDDQL	I/O3R	I/O3L	I/O4L
N1	N2	N3	N4	N5	N6	N7	N8	N9	N10	N11		N13	N14	N15	N16
I/O33L	I/O34R	I/ O 33R	PL/FTR	VDDQR	VDDQR	V DDQL	Vddql	Vddqr	VDDQR	VDDQL		VDD	I/O2L	I/O1R	I/O2R
P1	P2	P3	P4	P5	P6	P7	P8	P9	P10	P11	P12	P13	P14	P15	P16
I/O35R	I/O34L	TMS	B A 4R	B A 1R	A 10R	A 7R	BE1R	BE0R	CLKR	ADSR	A 6R	A 3R	I/OoL	I/O0R	I/O1L
R1	R2	R3	R4	R5	R6	R7	R8	R9	R10	R11	R12	R13	R14	R15	R16
I/O35L	NC	TRST	NC	BA3R	BA0R	A 9R	BE3R	CE0R	R/W R	REPEATR	A 4R	A 1R	OPTR	NC	NC
T1	T2	T3	T4	T5	T6	T7	T8	T9	T10	T11	T12	T13	T14	T15	T16
NC	TCK	NC	B A 5R	B A 2R	A 11R	A 8R	BE2R	CE1R	OEr	CNTENR	A 5R	A 2R	A 0R	NC	NC

5618 drw 02d

- 1. All VDD pins must be connected to 3.3V power supply.
- 2. All VDDQ pins must be connected to appropriate power supply: 3.3V if OPT pin for that port is set to VIH (3.3V), and 2.5V if OPT pin for that port is set to VIL (0V).
- 3. All Vss pins must be connected to ground supply.
- 4. Package body is approximately 17mm x 17mm x 1.4mm, with 1.0mm ball-pitch.
- 5. This package code is used to reference the package diagram.
- 6. This text does not indicate orientation of the actual part-marking.



Pin Configuration^(1,2,3,4) (con't.)



- 1. All VDD pins must be connected to 3.3V power supply.
- 2. All VDDQ pins must be connected to appropriate power supply: 3.3V if OPT pin for that port is set to VIH (3.3V), and 2.5V if OPT pin for that port is set to VIH (0V).
- 3. All Vss pins must be connected to ground supply.
- 4. Package body is approximately 28mm x 28mm x 3.5mm.
- 5. This package code is used to reference the package diagram.
- 6. This text does not indicate orientation of the actual part-marking.



Pin Names

Left Port	Right Port	Names			
CEOL, CE1L	CEOR, CE1R	Chip Enables			
R/WL	R/WR	Read/Write Enable			
ŌĒL	OE R	Output Enable			
BAOL - BA5L	BAor - BAsr	Bank Address ⁽⁴⁾			
A0L - A11L	A0R - A11R	Address			
1/O0L - 1/O35L	I/Oor - I/O35R	Data Input/Output			
CLKL	CLKR	Clock			
PL/FTL	PL/ FT R	Pipeline/Flow-Through			
ADS L	ADS R	Address Strobe Enable			
CNTENL	<u>CNTEN</u> R	Counter Enable			
REPEATL	REPEATR	Counter Repeat ⁽³⁾			
BEOL - BE3L	BEOR - BE3R	Byte Enables (9-bit bytes)			
VDDQL	VDDQR	Power (I/O Bus) (3.3V or 2.5V) ⁽¹⁾			
OPTL	OPTR	Option for selecting VDDQX ^(1,2)			
,	VDD	Power (3.3V) ⁽¹⁾			
,	Vss	Ground (0V)			
	TDI	Test Data Input			
1	TDO	Test Data Output			
1	ГСК	Test Logic Clock (10MHz)			
1	TMS	Test Mode Select			
Ŧ	RST	Reset (Initialize TAP Controller)			

5618 tbl 01

- VDD, OPTx, and VDDOx must be set to appropriate operating levels prior to applying inputs on the I/Os and controls for that port.
- 2. OPTx selects the operating voltage levels for the I/Os and controls on that port. If OPTx is set to VIH (3.3V), then that port's I/Os and controls will operate at 3.3V levels and VDDOX must be supplied at 3.3V. If OPTx is set to VIL (0V), then that port's I/Os and address controls will operate at 2.5V levels and VDDOX must be supplied at 2.5V. The OPT pins are independent of one another—both ports can operate at 3.3V levels, both can operate at 2.5V levels, or either can operate at 3.3V with the other at 2.5V.
- When REPEATx is asserted, the counter will reset to the last valid address loaded via ADSx.
- 4. Accesses by the ports into specific banks are controlled by the bank address pins under the user's direct control: each port can access any bank of memory with the shared array that is not currently being accessed by the opposite port (i.e., BAoL BA5L ≠ BAOR BA5R). In the event that both ports try to access the same bank at the same time, neither access will be valid, and data at the two specific addresses targeted by the ports within that bank may be corrupted (in the case that either or both ports are writing) or may result in invalid output (in the case that both ports are trying to read).



Truth Table I—Read/Write and Enable Control (1,2,3,4)

\overline{OE}^3	CLK	Œ	CE ₁	BE ₃	<u>B</u> E₂	<u>B</u> E₁	BE₀	R/W	Byte 3 I/O27-35	Byte 2 I/O ₁₈₋₂₆	Byte 1 I/O ₉₋₁₇	Byte 0 I/O ₀₋₈	MODE
Χ	1	Н	Х	Χ	Χ	Х	Χ	Х	High-Z	High-Z	High-Z	High-Z	Deselected-Power Down
Χ	1	Χ	L	Х	Χ	Х	Х	Х	High-Z	High-Z	High-Z	High-Z	Deselected-Power Down
Χ	1	L	Н	Н	Н	Н	Н	Х	High-Z	High-Z	High-Z	High-Z	All Bytes Deselected
Χ	\uparrow	L	Н	Н	Н	Н	L	L	High-Z	High-Z	High-Z	DIN	Write to Byte 0 Only
Χ	1	L	Н	Н	Н	L	Н	L	High-Z	High-Z	Din	High-Z	Write to Byte 1 Only
Χ	1	L	Н	Η	L	Н	Н	L	High-Z	Din	High-Z	High-Z	Write to Byte 2 Only
Χ	1	L	Н	L	Н	Н	Н	L	Din	High-Z	High-Z	High-Z	Write to Byte 3 Only
Χ	1	L	Н	Η	Н	L	L	L	High-Z	High-Z	Din	DIN	Write to Lower 2 Bytes Only
Χ	\uparrow	L	Н	Ш	L	Н	Н	L	Din	Din	High-Z	High-Z	Write to Upper 2 bytes Only
Χ	1	L	Н	L	L	L	L	L	Din	Din	Din	DIN	Write to All Bytes
L	↑	L	Н	Η	Н	Н	L	Н	High-Z	High-Z	High-Z	Dоит	Read Byte 0 Only
L	↑	L	Н	Η	Н	L	Н	Н	High-Z	High-Z	Dout	High-Z	Read Byte 1 Only
L	↑	L	Н	Η	L	Н	Н	Н	High-Z	Douт	High-Z	High-Z	Read Byte 2 Only
L	↑	L	Н	Ш	Н	Н	Н	Н	Douт	High-Z	High-Z	High-Z	Read Byte 3 Only
L	1	L	Н	Н	Н	L	L	Н	High-Z	High-Z	Dout	Dout	Read Lower 2 Bytes Only
L	\uparrow	L	Н	L	L	Н	Н	Н	Dоит	Douт	High-Z	High-Z	Read Upper 2 Bytes Only
L	1	L	Н	L	L	L	L	Н	Douт	Douт	Dout	Dout	Read All Bytes
Н	Χ	Χ	Χ	Χ	Χ	Χ	Х	Χ	High-Z	High-Z	High-Z	High-Z	Outputs Disabled

NOTES:

5618 tbl 02

- 1. "H" = VIH, "L" = VIL, "X" = Don't Care.
- 2. ADS, CNTEN, REPEAT are set as appropriate for address access. Refer to Truth Table II for details.
- 3. OE is an asynchronous input signal.
- 4. It is possible to read or write any combination of bytes during a given access. A few representative samples have been illustrated here.

Truth Table II—Address and Address Counter Control (1,2,7)

Address	Previous Address	Addr Used	CLK	ĀDS	CNTEN	REPEAT ⁽⁶⁾	I/O ⁽³⁾	MODE
An	Х	An	↑	L ⁽⁴⁾	Χ	Н	Dvo (n)	External Address Used
Х	An	An + 1	↑	Н	L ⁽⁵⁾	Н	Dvo(n+1)	Counter Enabled—Internal Address generation
Х	An + 1	An + 1	↑	Н	Н	Н	Dvo(n+1)	External Address Blocked—Counter disabled (An + 1 reused)
X	Х	An	1	X	Х	L ⁽⁴⁾	Dvo(0)	Counter Set to last valid ADS load

NOTES:

- 1. "H" = V_{IH} , "L" = V_{IL} , "X" = Don't Care.
- 2. Read and write operations are controlled by the appropriate setting of R/W, $\overline{\text{CE}}_0$, CE1, $\overline{\text{BE}}_n$ and $\overline{\text{OE}}$.
- 3. Outputs configured in flow-through output mode: if outputs are in pipelined mode the data out will be delayed by one cycle.
- 4. ADS and REPEAT are independent of all other memory control signals including CEo, CE1 and BEn
- 5. The address counter advances if CNTEN = VIL on the rising edge of CLK, regardless of all other memory control signals including CEo, CE1, BEn.
- 6. When REPEAT is asserted, the counter will reset to the last valid address loaded via ADS. This value is not set at power-up: a known location should be loaded via ADS during initialization if desired. Any subsequent ADS access during operations will update the REPEAT address location.
- 7. The counter includes bank address and internal address. The counter will advance across bank boundaries. For example, if the counter is in Bank 0, at address FFFh, and is advanced one location, it will move to address 0h in Bank 1. By the same token, the counter at FFFh in Bank 63 will advance to 0h in Bank 0. Refer to Timing Waveform of Counter Repeat, page 18. Care should be taken during operation to avoid having both counters point to the same bank (i.e., ensure BAoL BAsR), as this condition will invalidate the access for both ports. Please refer to the functional description on page 19 for details.

Recommended Operating Temperature and Supply Voltage⁽¹⁾

Grade	Ambient Temperature	GND	VDD	
Commercial	0°C to +70°C	0V	3.3V <u>+</u> 150mV	
Industrial	-40°C to +85°C	0V	3.3V <u>+</u> 150mV	

NOTE:

5618 tbl 04

1. This is the parameter Ta. This is the "instant on" case temperature.

Absolute Maximum Ratings(1)

Symbol	Rating	Commercial & Industrial	Unit
VTERM ⁽²⁾	Terminal Voltage with Respect to GND	-0.5 to +4.6	V
TBIAS	Temperature Under Bias	-55 to +125	°C
Tstg	Storage Temperature	-65 to +150	°C
Іоит	DC Output Current	50	mA

NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- 2. VTERM must not exceed VDD + 150mV for more than 25% of the cycle time or 4ns maximum, and is limited to \leq 20mA for the period of VTERM \geq VDD + 150mV.

Recommended DC Operating Conditions with VDDQ at 2.5V

Symbol	Parameter	Min.	Тур.	Мах.	Unit
VDD	Core Supply Voltage	3.15	3.3	3.45	٧
VDDQ	I/O Supply Voltage ⁽³⁾	2.4	2.5	2.6	٧
Vss	Ground	0	0	0	٧
VIH	Input High Voltage (Address & Control Inputs)	1.7	-	VDDQ + 100mV ⁽²⁾	V
VIH	Input High Voltage - I/O ⁽³⁾	1.7	_	VDDQ + 100mV ⁽²⁾	٧
VIL	Input Low Voltage	-0.3 ⁽¹⁾	_	0.7	٧

NOTES:

- 5618 tb1 05a
- 1. Undershoot of $Vil \ge -1.5V$ for pulse width less than 10ns is allowed.
- 2. VTERM must not exceed VDDQ + 100mV.
- To select operation at 2.5V levels on the I/Os and controls of a given port, the OPT pin for that port must be set to VIL (OV), and VDDOX for that port must be supplied as indicated above.

Recommended DC Operating Conditions with VDDQ at 3.3V

Symbol	Parameter	Min.	Тур.	Max.	Unit
VDD	Core Supply Voltage	3.15	3.3	3.45	٧
VDDQ	I/O Supply Voltage ⁽³⁾	3.15	3.3	3.45	٧
Vss	Ground	0	0	0	٧
VIH	Input High Voltage (Address & Control Inputs) ⁽³⁾	2.0	-	VDDQ + 150mV ⁽²⁾	V
VIH	Input High Voltage - I/O ⁽³⁾	2.0	-	VDDQ + 150mV ⁽²⁾	٧
VIL	Input Low Voltage	-0.3 ⁽¹⁾	-	0.8	٧

5618 tbl 05b

- 1. Undershoot of $V_{IL \ge} -1.5V$ for pulse width less than 10ns is allowed.
- 2. VTERM must not exceed VDDQ + 150mV.
- To select operation at 3.3V levels on the I/Os and controls of a given port, the OPT pin for that port must be set to ViH (3.3V), and VDDOX for that port must be supplied as indicated above.



70V7519S

High-Speed 256K x 36 Synchronous Bank-Switchable Dual-Port Static RAM

Capacitance⁽¹⁾

(TA = +25°C, F = 1.0MHz) PQFP ONLY

Symbol	Parameter	Conditions ⁽²⁾	Max.	Unit
CIN	Input Capacitance	VIN = 3dV	8	pF
Cout ⁽³⁾	Output Capacitance	Vout = 3dV	10.5	pF

5618 tbl

NOTES:

- 1. These parameters are determined by device characterization, but are not production tested.
- 2. $\overline{\mbox{3dV}}$ references the interpolated capacitance when the input and output switch from 0V to 3V or from 3V to 0V.
- 3. Cout also references Ci/o.

DC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range (VDD = 3.3V ± 150mV)

			70V7	′519S	
Symbol	Parameter	Test Conditions	Min.	Max.	Unit
111	Input Leakage Current ⁽¹⁾	VDDQ = Max., VIN = 0V to VDDQ	_	10	μΑ
ILO	Output Leakage Current ⁽¹⁾	\overline{CE}_0 = Vih or CE1 = Vil., Vout = 0V to VDDQ		10	μΑ
Vol (3.3V)	Output Low Voltage ⁽²⁾	IOL = +4mA, $VDDQ = Min$.		0.4	V
Voн (3.3V)	Output High Voltage ⁽²⁾	IOH = -4mA, VDDQ = Min.	2.4		V
Vol (2.5V)	Output Low Voltage ⁽²⁾	IOL = +2mA, $VDDQ = Min$.	_	0.4	V
Voн (2.5V)	Output High Voltage ⁽²⁾	IOH = -2mA, VDDQ = Min.	2.0	_	V

NOTES:

- 1. At $VDD \le 2.0V$ leakages are undefined.
- 2. VDDQ is selectable (3.3V/2.5V) via OPT pins. Refer to p.5 for details.



DC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range⁽⁵⁾ (VDD = 3.3V ± 150mV)

70V7519S200⁽⁷⁾ 70V7519S166⁽⁶⁾ 70V7519S133 Com'l Only Com'l Com'l & Ind & Ind Typ.⁽⁴⁾ Typ.(4) Typ.(4) Symbol Parameter **Test Condition** Version Max. Max. Max. Unit IDD Dynamic Operating CEL and CER= VIL. COM'L S 550 mΑ 815 950 675 790 645 Current (Both Outputs Disabled, Ports Active) $f = fMAX^{(1)}$ IND S 675 830 550 675 Standby Current $\overline{CE}L = \overline{CE}R = VIH$ S mΑ ISB1 COM'L 340 410 275 340 250 295 (Both Ports - TTL $f = fMAX^{(1)}$ IND Level Inputs) S 275 355 250 310 Standby Current \overline{CE} "A" = VIL and \overline{CE} "B" = VIH⁽³⁾ ISB2 mA COM'L S 690 770 515 640 460 520 (One Port - TTL Active Port Outputs Disabled, Level Inputs) f=fMAX⁽¹⁾ IND S 515 660 460 545 Both Ports $\overline{CE}L$ and $\overline{CE}R \ge VDDQ - 0.2V$, ISB3 Full Standby Current COM'L S 10 30 10 30 mΑ $VIN \ge VDDQ - 0.2V$ or $VIN \le 0.2V$, (Both Ports - CMOS S $f = 0^{(2)}$ IND Level Inputs) 10 40 10 40 Full Standby Current $\overline{\text{CE}}$ "A" $\leq 0.2V$ and $\overline{\text{CE}}$ "B" $\geq V$ DDQ - $0.2V^{(5)}$ ISB4 mΑ COM'L S 690 770 515 640 460 520 (One Port - CMOS $VIN \ge VDDQ - 0.2V$ or $VIN \le 0.2V$, Level Inputs) Active Port, Outputs Disabled, S IND 515 660 460 545 $f = fMAX^{(1)}$

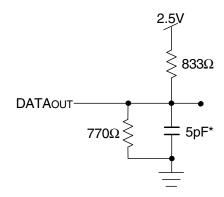
5618 thl 0

- 1. At f = fmax, address and control lines (except Output Enable) are cycling at the maximum frequency clock cycle of 1/tcyc, using "AC TEST CONDITIONS" at input levels of GND to 3V.
- 2. f = 0 means no address, clock, or control lines change. Applies only to input at CMOS level standby.
- 3. Port "A" may be either left or right port. Port "B" is the opposite from port "A".
- 4. VDD = 3.3V, TA = 25°C for Typ, and are not production tested. IDD DC(f=0) = 120mA (Typ).
- 5. $\overline{CE}x = VIL \text{ means } \overline{CE}ox = VIL \text{ and } CE1x = VIH$
 - $\overline{CE}x = VIH \text{ means } \overline{CE}0x = VIH \text{ or } CE1x = VIL$
 - $\overline{\text{CE}}\text{x} \leq 0.2 \text{V}$ means $\overline{\text{CE}}\text{ox} \leq 0.2 \text{V}$ and $\text{CE}\text{1x} \geq \text{V}\text{DDQ}$ 0.2 V
 - $\overline{\text{CE}}$ x \geq VDDQ 0.2V means $\overline{\text{CE}}$ 0x \geq VDDQ 0.2V or CE1x \leq 0.2V
 - "X" represents "L" for left port or "R" for right port.
- 6. 166MHz Industrial Temperature not available in BF208 package.
- 7. This speed grade available when VDDQ = 3.3.V for a specific port (i.e., OPTx = ViH). This speed grade available in BC-256 package only.



AC Test Conditions	(VDD0 - 3 3V/2 5V)
AC 1631 CONDITIONS	(V DDQ - 3.3 V/Z.3 V /

10 1031 0011d1t10113 (VDDQ - 3.3 V/2.3 V)				
Input Pulse Levels (Address & Controls)	GND to 3.0V/GND to 2.4V			
Input Pulse Levels (I/Os)	GND to 3.0V/GND to 2.4V			
Input Rise/Fall Times	2ns			
Input Timing Reference Levels	1.5V/1.25V			
Output Reference Levels	1.5V/1.25V			
Output Load	Figures 1 and 2			



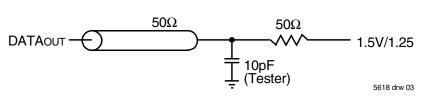


Figure 1. AC Output Test load.

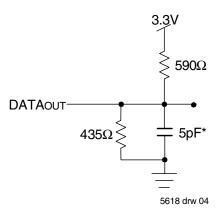


Figure 2. Output Test Load (For tcklz, tckHz, tolz, and toHz). *Including scope and jig.

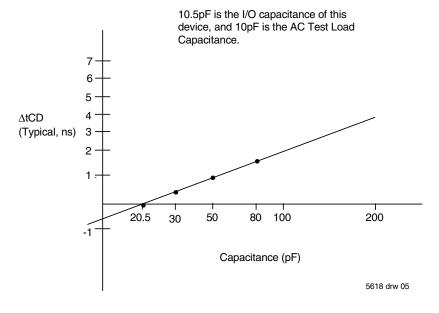


Figure 3. Typical Output Derating (Lumped Capacitive Load).



AC Electrical Characteristics Over the Operating Temperature Range (Read and Write Cycle Timing) $^{(2,3)}$ (VDD = 3.3V ± 150mV, TA = 0°C to +70°C)

	and write cycle Timing) (VDD = 3.3V ±	70V7519S200 ⁽⁵⁾ Com'l Only		70V7519S166 ^(3,4) Com'l & Ind		70V7519S133 ⁽³⁾ Com'l & Ind		
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Unit
tcvc1	Clock Cycle Time (Flow-Through) ⁽¹⁾	15	_	20	_	25		ns
tcvc2	Clock Cycle Time (Pipelined) ⁽¹⁾	5	_	6	_	7.5		ns
tcH1	Clock High Time (Flow-Through) ⁽¹⁾	5	_	6	_	7	_	ns
tCL1	Clock Low Time (Flow-Through) ⁽¹⁾	5	_	6	_	7	_	ns
tCH2	Clock High Time (Pipelined) ⁽²⁾	2.0	_	2.1	_	2.6	_	ns
tCL2	Clock Low Time (Pipelined) ⁽¹⁾	2.0	_	2.1	_	2.6	_	ns
tr	Clock Rise Time	_	1.5	_	1.5	_	1.5	ns
tF	Clock Fall Time	_	1.5	_	1.5	_	1.5	ns
tsa	Address Setup Time	1.5	_	1.7	_	1.8	_	ns
tha	Address Hold Time	0.5	_	0.5	_	0.5	_	ns
tsc	Chip Enable Setup Time	1.5	_	1.7	_	1.8	_	ns
thc	Chip Enable Hold Time	0.5	_	0.5	_	0.5	_	ns
tsB	Byte Enable Setup Time	1.5	_	1.7	_	1.8	_	ns
tнв	Byte Enable Hold Time	0.5	_	0.5	_	0.5	_	ns
tsw	R/W Setup Time	1.5	_	1.7	_	1.8	_	ns
thw	R/W Hold Time	0.5	_	0.5	_	0.5	_	ns
tsd	Input Data Setup Time	1.5	_	1.7	_	1.8		ns
thd	Input Data Hold Time	0.5	_	0.5	_	0.5		ns
tsad	ADS Setup Time	1.5	_	1.7	_	1.8	_	ns
thad	ADS Hold Time	0.5	_	0.5	_	0.5	_	ns
tscn	CNTEN Setup Time	1.5	_	1.7	_	1.8	_	ns
thcn	CNTEN Hold Time	0.5	_	0.5	_	0.5	_	ns
tsrpt	REPEAT Setup Time	1.5	_	1.7	_	1.8	_	ns
thrpt	REPEAT Hold Time	0.5	_	0.5	_	0.5	_	ns
toe	Output Enable to Data Valid		4.0	_	4.0	_	4.2	ns
tolz	Output Enable to Output Low-Z	0.5	_	0.5	_	0.5	_	ns
tонz	Output Enable to Output High-Z	1	3.4	1	3.6	1	4.2	ns
tCD1	Clock to Data Valid (Flow-Through) ⁽¹⁾		10	_	12	_	15	ns
tCD2	Clock to Data Valid (Pipelined) ⁽¹⁾	_	3.4	_	3.6	_	4.2	ns
toc	Data Output Hold After Clock High	1	_	1	_	1	_	ns
tckhz	Clock High to Output High-Z	1	3.4	1	3.6	1	4.2	ns
tcklz	Clock High to Output Low-Z	0.5	_	0.5	_	0.5	_	ns
Port-to-Port D	Port-to-Port Delay							
tco	Clock-to-Clock Offset	5.0		6.0	_	7.5		ns

NOTES:

^{1.} The Pipelined output parameters (tcyc2, tcb2) apply to either or both left and right ports when FT/PIPEx = VIH. Flow-through parameters (tcyc1, tcb1) apply when FT/PIPEx = VIL for that port.

^{2.} All input signals are synchronous with respect to the clock except for the asynchronous Output Enable (OE) and FT/PIPE. FT/PIPE should be treated as a DC signal, i.e. steady state during operation.

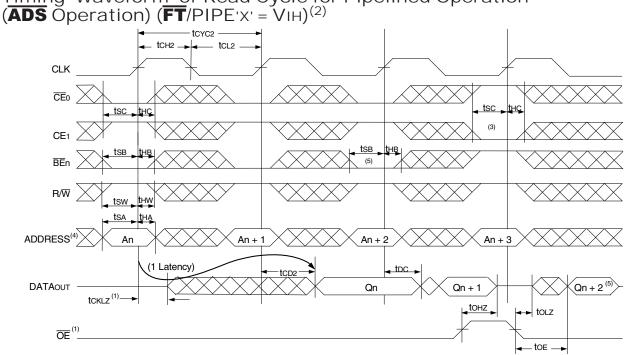
^{3.} These values are valid for either level of VDDQ (3.3V/2.5V). See page 5 for details on selecting the desired operating voltage levels for each port.

^{4. 166}MHz Industrial Temperature not available in BF208 package.

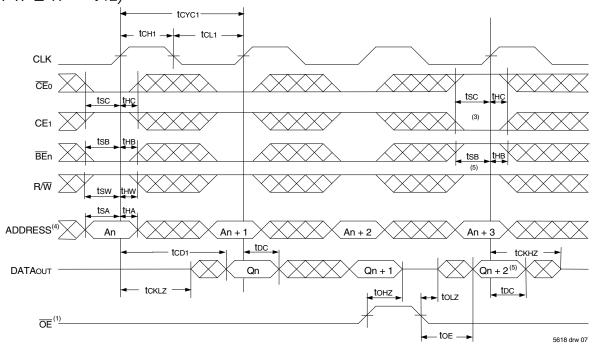
^{5.} This speed grade available when VDDQ = 3.3.V for a specific port (i.e., OPTx = ViH). This speed grade available in BC256 package only.

5618 drw 06

Timing Waveform of Read Cycle for Pipelined Operation

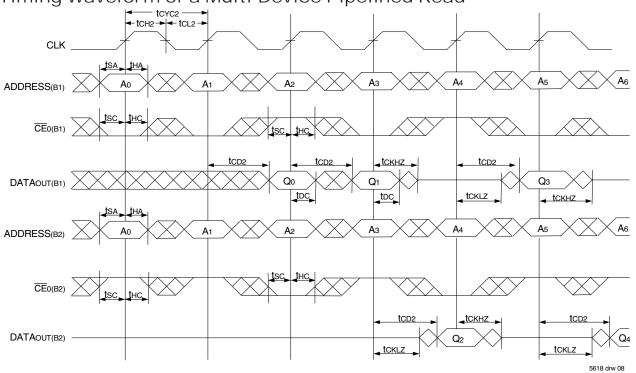


Timing Waveform of Read Cycle for Flow-through Output $(\overline{FT}/PIPE"x" = VIL)^{(2,6)}$

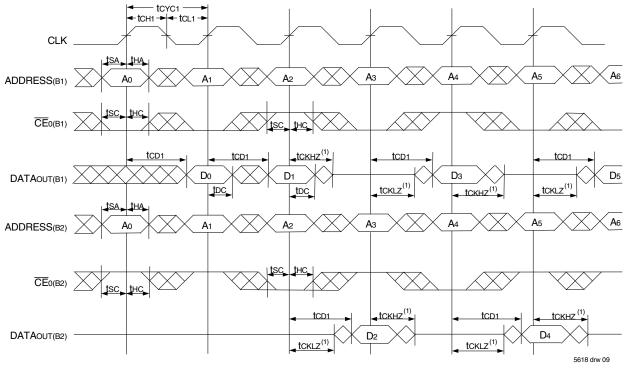


- 1. \overline{OE} is asynchronously controlled; all other inputs are synchronous to the rising clock edge.
- 2. ADS = VIL, CNTEN and REPEAT = VIH.
- 3. The output is disabled (High-Impedance state) by $\overline{\text{CE}}_0 = \text{V}_{IH}$, $\text{CE}_1 = \text{V}_{IL}$, $\overline{\text{BE}}_{\text{n}} = \text{V}_{IH}$ following the next rising edge of the clock. Refer to Truth Table 1.
- 4. Addresses do not have to be accessed sequentially since $\overline{ADS} = V_{IL}$ constantly loads the address on the rising edge of the CLK; numbers are for reference use only.
- 5. If BEn was HIGH, then the appropriate Byte of DATAout for Qn + 2 would be disabled (High-Impedance state).
- 6. "x" denotes Left or Right port. The diagram is with respect to that port.

Timing Waveform of a Multi-Device Pipelined Read (1,2)



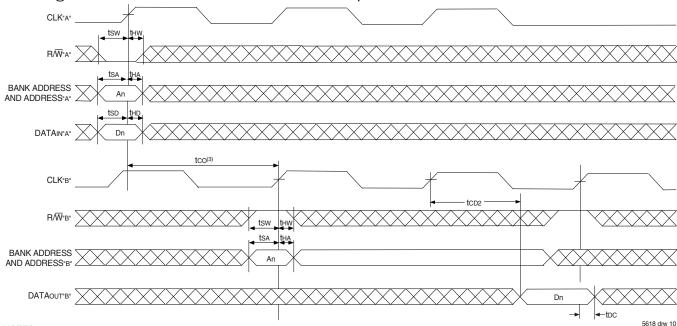
Timing Waveform of a Multi-Device Flow-Through Read^(1,2)



- B1 Represents Device #1; B2 Represents Device #2. Each Device consists of one IDT70V7519 for this waveform, and are setup for depth expansion in this example. ADDRESS(B1) = ADDRESS(B2) in this situation.
- 2. $\overline{BE}n$, \overline{OE} , and $\overline{ADS} = VIL$; $\overline{CE1(B1)}$, $\overline{CE1(B2)}$, $\overline{R/W}$, \overline{CNTEN} , and $\overline{REPEAT} = VIH$.



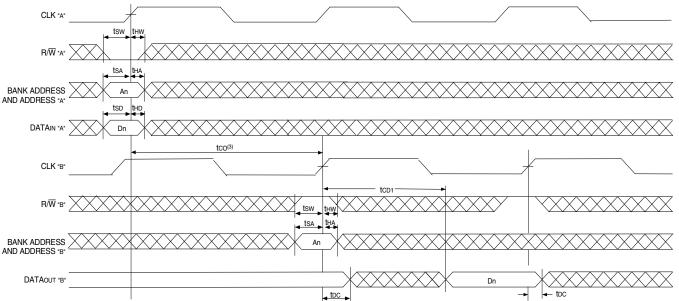
Timing Waveform of Port A Write to Pipelined Port B Read^(1,2,4)



NOTES:

- 1. \overline{CE}_0 , \overline{BE}_n , and $\overline{ADS} = VIL$; CE1, \overline{CNTEN} , and $\overline{REPEAT} = VIH$.
- 2. \overline{OE} = VIL for Port "B", which is being read from. \overline{OE} = VIH for Port "A", which is being written to.
- 3. If tco < minimum specified, then operations from both ports are INVALID. If tco ≥ minimum, then data from Port "B" read is available on first Port "B" clock cycle (ie, time from write to valid read on opposite port will be tco + tcyc2 + tcb2).
- 4. All timing is the same for Left and Right ports. Port "A" may be either Left or Right port. Port "B" is the opposite of Port "A"

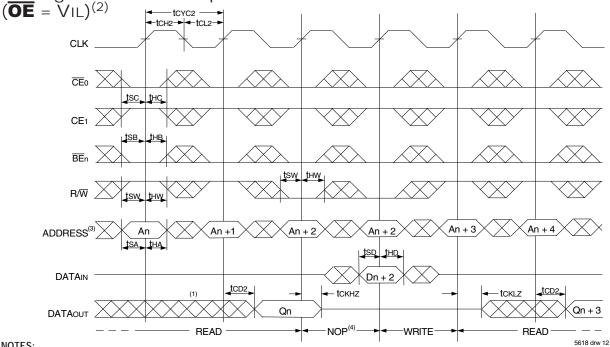
Timing Waveform with Port-to-Port Flow-Through Read^(1,2,4)



- 1. $\overline{CE_0}$, $\overline{BE}n$, and $\overline{ADS} = VIL$; CE_1 , \overline{CNTEN} , and $\overline{REPEAT} = VIH$.
- 2. $\overline{OE} = V_{IL}$ for the Right Port, which is being read from. $\overline{OE} = V_{IH}$ for the Left Port, which is being written to.
- 3. If tco < minimum specified, then operations from both ports are INVALID. If tco ≥ minimum, then data from Port "B" read is available on first Port "B" clock cycle (i.e., time from write to valid read on opposite port will be tco + tco1).
- 4. All timing is the same for both left and right ports. Port "A" may be either left or right port. Port "B" is the opposite of Port "A".

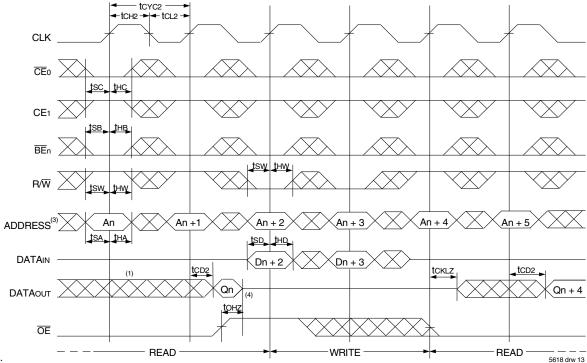


Timing Waveform of Pipelined Read-to-Write-to-Read



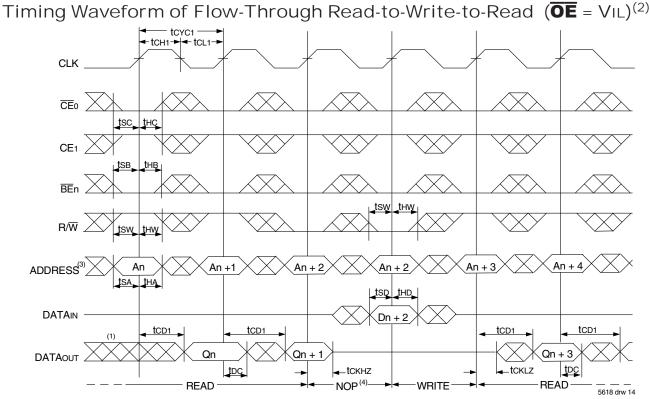
- Output state (High, Low, or High-impedance) is determined by the previous cycle control signals.
- CEo, BEn, and ADS = VIL; CE1, CNTEN, and REPEAT = VIH. "NOP" is "No Operation".
- 3. Addresses do not have to be accessed sequentially since ADS = VIL constantly loads the address on the rising edge of the CLK; numbers are for reference use only.
- 4. "NOP" is "No Operation." Data in memory at the selected address may be corrupted and should be rewritten to guarantee data integrity.

Timing Waveform of Pipelined Read-to-Write-to-Read (**OE** Controlled)⁽²⁾

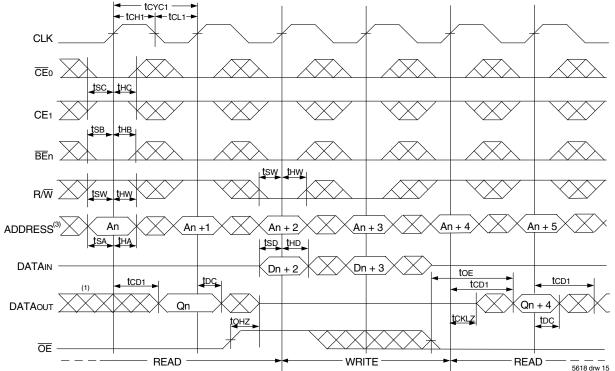


- 1. Output state (High, Low, or High-impedance) is determined by the previous cycle control signals.
- \overline{CE}_0 , \overline{BE}_n , and $\overline{ADS} = VIL$; CE_1 , \overline{CNTEN} , and $\overline{REPEAT} = VIH$.
- 3. Addresses do not have to be accessed sequentially since ADS = VIL constantly loads the address on the rising edge of the CLK; numbers are for reference
- This timing does not meet requirements for fastest speed grade. This waveform indicates how logically it could be done if timing so allows.





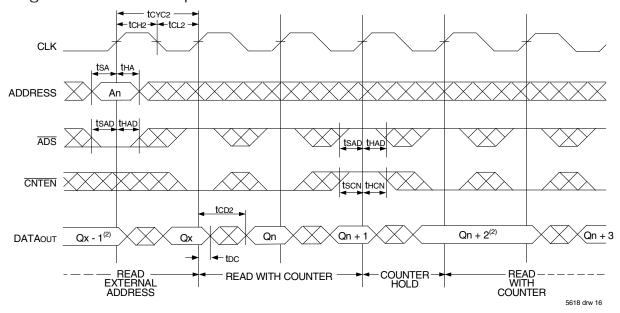
Timing Waveform of Flow-Through Read-to-Write-to-Read (**OE** Controlled)⁽²⁾



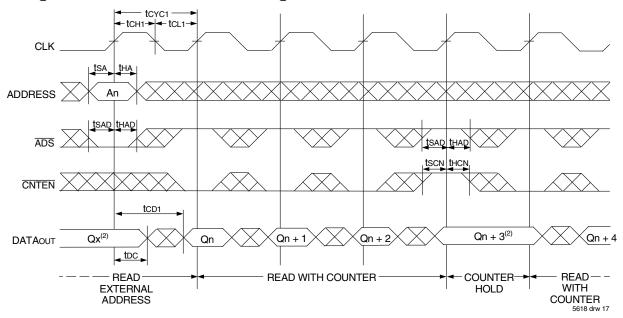
- 1. Output state (High, Low, or High-impedance) is determined by the previous cycle control signals.
- 2. $\overline{CE_0}$, \overline{BE} n, and \overline{ADS} = VIL; CE1, \overline{CNTEN} , and \overline{REPEAT} = VIH.
- 3. Addresses do not have to be accessed sequentially since ADS = VIL constantly loads the address on the rising edge of the CLK; numbers are for reference use only.
- "NOP" is "No Operation." Data in memory at the selected address may be corrupted and should be rewritten to guarantee data integrity.



Timing Waveform of Pipelined Read with Address Counter Advance⁽¹⁾



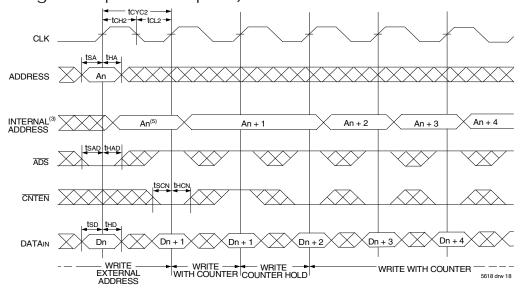
Timing Waveform of Flow-Through Read with Address Counter Advance⁽¹⁾



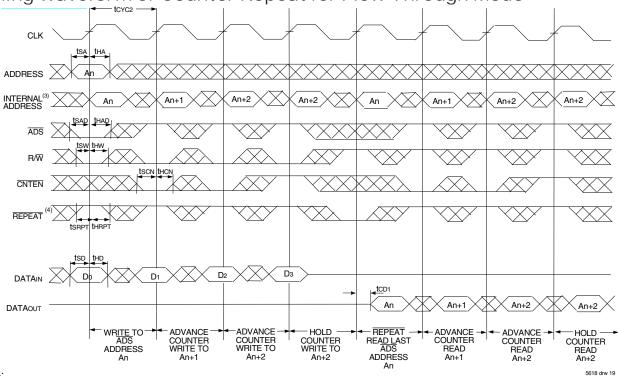
- 1. \overline{CE}_0 , \overline{OE} , $\overline{BE}_0 = VIL$; CE_1 , R/\overline{W} , and $\overline{REPEAT} = VIH$.
- 2. If there is no address change via $\overline{ADS} = VIL$ (loading a new address) or $\overline{CNTEN} = VIL$ (advancing the address), i.e. $\overline{ADS} = VIH$ and $\overline{CNTEN} = VIH$, then the data output remains constant for subsequent clocks.

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Timing Waveform of Write with Address Counter Advance (Flow-through or Pipelined Inputs)^(1,6)



Timing Waveform of Counter Repeat for Flow Through Mode (2,6,7)



- 1. \overline{CE}_0 , \overline{BE}_n , and $R/\overline{W} = V_{IL}$; CE_1 and $\overline{REPEAT} = V_{IH}$.
- 2. \overline{CE}_0 , $\overline{BE}_n = VIL$; $CE_1 = VIH$.
- 3. The "Internal Address" is equal to the "External Address" when $\overline{ADS} = VIL$ and equals the counter output when $\overline{ADS} = VIL$
- 4. No dead cycle exists during REPEAT operation. A READ or WRITE cycle may be coincidental with the counter REPEAT cycle: Address loaded by last valid ADS load will be accessed. For more information on REPEAT function refer to Truth Table II.
- 5. CNTEN = VIL advances Internal Address from 'An' to 'An +1'. The transition shown indicates the time required for the counter to advance. The 'An +1'Address is written to during this cycle.
- 6. The counter includes bank address and internal address. The counter will advance across bank boundaries. For example, if the counter is in Bank 0, at address FFFh, and is advanced one location, it will move to address 0h in Bank 1. By the same token, the counter at FFFh in Bank 63 will advance to 0h in Bank 0.
- 7. For Pipelined Mode user should add 1 cycle latency for outputs as per timing waveform of read cycle for pipelined operations.



Functional Description

The IDT70V7519 is a high-speed 256Kx36 (9 Mbit) synchronous Bank-Switchable Dual-Ported SRAM organized into 64 independent 4Kx36 banks. Based on a standard SRAM core instead of a traditional true dual-port memory core, this bank-switchable device offers the benefits of increased density and lower cost-per-bit while retaining many of the features of true dual-ports. These features include simultaneous, random access to the shared array, separate clocks per port, 166 MHz operating speed, full-boundary counters, and pinouts compatible with the IDT70V3599 (128Kx36) dual-port family.

The two ports are permitted independent, simultaneous access into separate banks within the shared array. Access by the ports into specific banks are controlled by the bank address pins under the user's direct control: each port can access any bank of memory with the shared array that is not currently being accessed by the opposite port (i.e., BAOL - BA5L \neq BAOR - BA5R). In the event that both ports try to access the same bank at the same time, neither access will be valid, and data at the two specific addresses targeted by the ports within that bank may be corrupted (in the case that either or both ports are writing) or may result in invalid output (in the case that both ports are trying to read).

The IDT70V7519 provides a true synchronous Dual-Port Static RAM

interface. Registered inputs provide minimal setup and hold times on address, data and all critical control inputs.

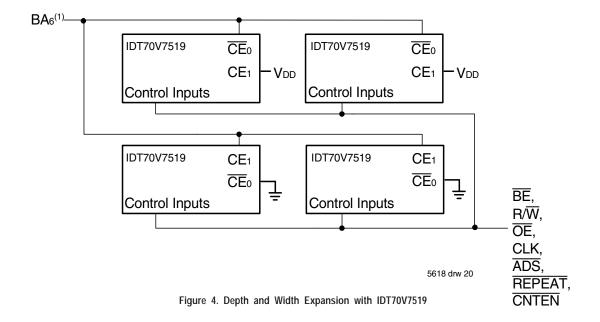
An asynchronous output enable is provided to ease asynchronous bus interfacing. Counter enable inputs are also provided to stall the operation of the address counters for fast interleaved memory applications.

A HIGH on $\overline{\text{CE}}$ 0 or a LOW on CE1 for one clock cycle will power down the internal circuitry on each port (individually controlled) to reduce static power consumption. Dual chip enables allow easier banking of multiple IDT70V7519s for depth expansion configurations. Two cycles are required with $\overline{\text{CE}}$ 0 LOW and CE1 HIGH to read valid data on the outputs.

Depth and Width Expansion

The IDT70V7519 features dual chip enables (refer to Truth Table I) in order to facilitate rapid and simple depth expansion with no requirements for external logic. Figure 4 illustrates how to control the various chip enables in order to expand two devices in depth.

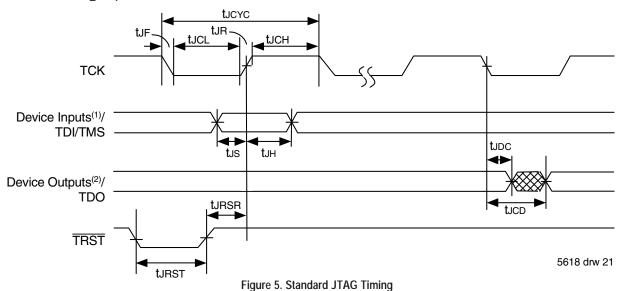
The IDT70V7519 can also be used in applications requiring expanded width, as indicated in Figure 4. Through combining the control signals, the devices can be grouped as necessary to accommodate applications needing 72-bits or wider.



NOTE:

1. In the case of depth expansion, the additional address pin logically serves as an extension of the bank address. Accesses by the ports into specific banks are controlled by the bank address pins under the user's direct control: each port can access any bank of memory within the shared array that is not currently being accessed by the opposite port (i.e., BAoL - BAoR - BAoR). In the event that both ports try to access the same bank at the same time, neither access will be valid, and data at the two specific addresses targeted by the parts within that bank may be corrupted (in the case that either or both parts are writing) or may result in invalid output (in the case that both ports are trying to read).

JTAG Timing Specifications



NOTES:

- 1. Device inputs = All device inputs except TDI, TMS, TRST, and TCK.
- 2. Device outputs = All device outputs except TDO.

JTAG AC Electrical Characteristics^(1,2,3,4)

		70V7519		
Symbol	Parameter	Min.	Max.	Units
ticyc	JTAG Clock Input Period	100	_	ns
исн	JTAG Clock HIGH	40		ns
tucı	JTAG Clock Low	40		ns
tır	JTAG Clock Rise Time	_	3 ⁽¹⁾	ns
₩F	JTAG Clock Fall Time	_	3 ⁽¹⁾	ns
URST	JTAG Reset	50		ns
tursr	JTAG Reset Recovery	50		ns
tuco	JTAG Data Output	_	25	ns
tudo	JTAG Data Output Hold	0		ns
tıs	JTAG Setup	15	_	ns
tлн	JTAG Hold	15	_	ns

NOTES:

- 1. Guaranteed by design.
- 2. 30pF loading on external output signals.
- 3. Refer to AC Electrical Test Conditions stated earlier in this document.
- 4. JTAG operations occur at one speed (10MHz). The base device may run at any speed specified in this datasheet.



Identification Register Definitions

Instruction Field	Value	Description
Revision Number (31:28)	0x0	Reserved for version number
IDT Device ID (27:12)	0x300	Defines IDT part number
IDT JEDEC ID (11:1)	0x33	Allows unique identification of device vendor as IDT
ID Register Indicator Bit (Bit 0)	1	Indicates the presence of an ID register

5618 tbl 13

Scan Register Sizes

Register Name	Bit Size
Instruction (IR)	4
Bypass (BYR)	1
Identification (IDR)	32
Boundary Scan (BSR)	Note (3)

5618 tbl 14

System Interface Parameters

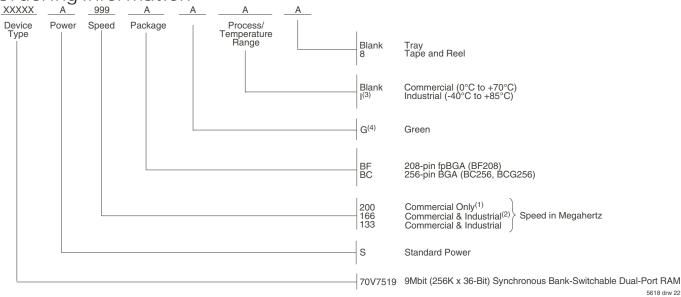
Instruction	Code	Description
EXTEST	0000	Forces contents of the boundary scan cells onto the device outputs ⁽¹⁾ . Places the boundary scan register (BSR) between TDI and TDO.
BYPASS	1111	Places the bypass register (BYR) between TDI and TDO.
IDCODE	0010	Loads the ID register (IDR) with the vendor ID code and places the register between TDI and TDO.
HIGHZ	0100	Places the bypass register (BYR) between TDI and TDO. Forces all device output drivers to a High-Z state.
CLAMP	0011	Uses BYR. Forces contents of the boundary scan cells onto the device outputs. Places the bypass register (BYR) between TDI and TDO.
SAMPLE/PRELOAD	0001	Places the boundary scan register (BSR) between TDI and TDO. SAMPLE allows data from device inputs ⁽²⁾ and outputs ⁽¹⁾ to be captured in the boundary scan cells and shifted serially through TDO. PRELOAD allows data to be input serially into the boundary scan cells via the TDI.
RESERVED	All other codes	Several combinations are reserved. Do not use codes other than those identified above.

NOTES:

- 1. Device outputs = All device outputs except TDO.
- 2. Device inputs = All device inputs except TDI, TMS, TRST, and TCK.
- 3. The Boundary Scan Descriptive Language (BSDL) file for this device is available on the IDT website (www.idt.com), or by contacting your local IDT sales representative.



Ordering Information



NOTES:

- Available in BC256 package only.
- 2. Industrial Temperature at 166Mhz not available in BF208 package.
- 3. Contact your local sales office for industrial temprange for other speeds, packages and powers.
- 4. Green parts available. For specific speeds, packages and powers contact your local sales office. LEAD FINISH (SnPb) parts are Obsolete excluding BGA & fpBGA. Product Discontinuation Notice - PDN# SP-17-02 Note that information regarding recently obsoleted parts are included in this datasheet for customer convenience.

Orderable Part Information

Speed (MHz)	Orderable Part ID	Pkg. Code	Pkg. Type	Temp. Grade
133	70V7519S133BC	BC256	CABGA	С
	70V7519S133BC8	BC256	CABGA	С
	70V7519S133BCI	BC256	CABGA	I
	70V7519S133BCl8	BC256	CABGA	I
	70V7519S133BF	BF208	CABGA	С
	70V7519S133BF8	BF208	CABGA	С
	70V7519S133BFI	BF208	CABGA	I
	70V7519S133BFI8	BF208	CABGA	I
166	70V7519S166BC	BC256	CABGA	С
	70V7519S166BC8	BC256	CABGA	С
	70V7519S166BCI	BC256	CABGA	ı
	70V7519S166BCl8	BC256	CABGA	ı
	70V7519S166BF	BF208	CABGA	С
	70V7519S166BF8	BF208	CABGA	С
200	70V7519S200BC	BC256	CABGA	С
	70V7519S200BC8	BC256	CABGA	С
	70V7519S200BCG	BCG256	CABGA	С
	70V7519S200BCG8	BCG256	CABGA	С

Datasheet Document History:

01/05/00: Initial Public Offering

10/19/01: Page 2, 3 & 4 Added date revision for pin configurations

Page 9 Changed IsB3 values for commercial and industrial DC Electrical Characteristics

Page 11 Changed to Evalue in AC Electrical Characteristics, please refer to Errata #SMEN-01-05

Page 20 Increased tJcD from 20ns to 25ns, please refer to Errata #SMEN-01-04

Page 1 & 22 Replaced TM logo with ® logo

01/11/02: Page 2 Corrected BF-208 pinout configuration fpBGA A15

03/18/02: Page 1, 9, 11 & 22 Added 200MHz specification

Page 9 Tightened power numbers in DC Electrical Characteristics

Page 14 Changed waveforms to show INVALID operation from opposite ports if tco < minimum specified

Page 1 - 22 Removed "Preliminary" status

12/04/02: Page 9, 11 & 22 Designated 200Mhz speed grade available in BC-256 package only

01/16/04: Page 11 Added byte enable setup time and byte enable hold time parameters and values to all speed grades in the AC

Electrical Characteristics Table

07/25/08: Page 9 Corrected a typo in the DC Chars table 01/29/09: Page 22 Removed "IDT" from orderable part number

06/04/15: Page 1 Added Green availability to Features

Page 2, 3, 4 & 22 The package codes for BF-208 changed to BF208, BC-256 changed to BC256, and DR-208 changed

to DR208 respectively to match the standard package codes

Page 2, 3 & 4 Removed the date from all of the pin configurations BF208, BC256 & DR208 Page 22 Added Green and T&R indicators and the correlating footnotes to Ordering Information

06/22/18: Product Discontinuation Notice - PDN# SP-17-02

Last time buy expires June 15, 2018

10/16/19: Page 1 & 22 Deleted obsolete DR208 PQFP package code

Page 2 & 3 Updated package codes

Page 22 Added Orderable Part Information table

11/01/19: Page 22 Corrected "ns" to "MHz" in the header of the Orderable Part Information table